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TEST REPORT

Part 15 Subpart C 15.247 & IC RSS-210(Issue 8)

Equipment under test	Keyless Entry System
Model name	MR1040-1WAY(Variant model: REB500-1WAY)
FCC ID	VA5JR1040-1WSSL
IC Certification	7087A-1WR1040SSL
Applicant	SEGI LIMITED
Manufacturer	SEGI ELECTRONICS CO.,LTD.
Date of test(s)	2012.03.27 ~ 2012.04.10
Date of issue	2012.04.17

Issued to

SEGI LIMITED
ROOM 1808, 18/F, Tower 2, Admiralty Centre, 18 Harcourt Rd.,
Admiralty, Hong Kong, China

Issued by

KES Co., Ltd.
C3701 Dongil Techno Town, 889-1, Gwanyang 2-dong, Dongan-gu, Anyang-si,
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Test and report completed by :	**Report approval by :**
	
Jeff Do Test engineer	Gyu-cheol Shin Technical manager

Revision history

Revision	Date of issue	Test report No.	Description
-	2012.04.17	KES-RF-120025	Initial

TABLE OF CONTENTS

1.0 General product description

Equipment under test	Keyless Entry System
Model name	MR1040-1WAY(Variant model: REB500-1WAY)
Serial number	N/A
Frequency Range	910.92 ㎒ ~ 919.08 ㎒
Modulation technique	FHSS
Number of channels	25
Antenna type & gain	Helical antenna / -8.586 dBi
Power source	DC 6 V

1.1 Test frequency

	Low channel	**Middle channel**	**High channel**
Frequency (㎒)	910.92	915.00	919.08

1.2 Information about variant model

Please refer to the family model cover letter.

1.3 Device modifications

No modifications were made during testing.

1.4 Test facility

C3701 Dongil Techno Town, 889-1, Gwanyang 2-dong, Dongan-gu, Anyang-si, Gyeonggi-do, 431-716, Korea
477-6, Hageo-ri, Yeoju-eup, Yeoju-gun, Gyeonggi-do, 469-803, Korea

The sites are constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22.

1.5 Test measurement procedure

The measurement procedure described in the American National Standard for Testing Unlicensed Wireless Devices (ANSI C63.4-2003) and FCC Public Notice DA 00-705 dated March 30, 2000 entitled "Filing and Measurement Guidelines for Frequency Hopping Spread Spectrum Systems"

1.6 Laboratory accreditations and listings

Country	Agency	Scope of accreditation	Logo
USA	FCC	3 & 10 meter Open Area Test Sites and one conducted site to perform FCC Part 15/18 measurements.	343818
KOREA	KC	EMI (10 meter Open Area Test Site and two conducted sites) Radio (3 & 10 meter Open Area Test Sites and one conducted site)	KR0100
Canada	IC	3 & 10 meter Open Area Test Sites and one conducted site	4769B-1

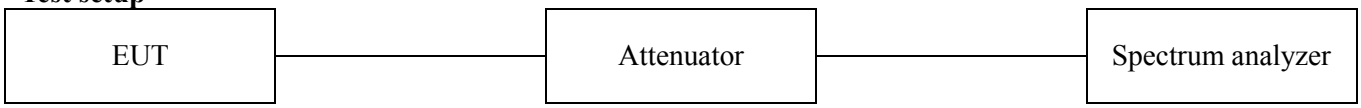
2.0 Summary of tests

Section in FCC Part 15 & RSS-210	Parameter	Status
15.247(b)(2) RSS-210 8.4(1)	Maximum peak output power	C
15.247(d) RSS-210 A8.5	Conducted spurious emission & band edge	C
15.247(a)(1)(i) RSS-210 A8.1(c)	20 dB bandwidth	C
15.247(a)(1) RSS-210 A8.1(b)	Frequency separation	C
15.247(b)(2) RSS-210 A8.1(c)	Number of hopping frequency	C
15.247(a)(1)(i) RSS-210 A8.1(c)	Time of occupancy(Dwell time)	C
15.247(d) RSS-210 A8.5	Radiated spurious emission & band edge	C
RSS-Gen 4.6.1	99 % Occupied bandwidth	C
Note 1: C=Complies NC=Not complies NT=Not tested NA=Not applicable		

2.1 Test data

2.1.1 Maximum peak power

Test setup



Test procedure

1. Use the following spectrum analyzer setting
   Center frequency: Lowest, middle and highest channels
   Span = 5 ㎒ (Approximately 5 times the 20 ㏈ bandwidth, centered on a hopping channel)
   RBW = 1 ㎒ (the 20 ㏈ bandwidth of the emission being measured)
   VBW = 1 ㎒ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
2. Allow the trace to stabilize. Use the marker-to-peak function to set the marker to the peak of the emission. The indicated level is the peak output power.

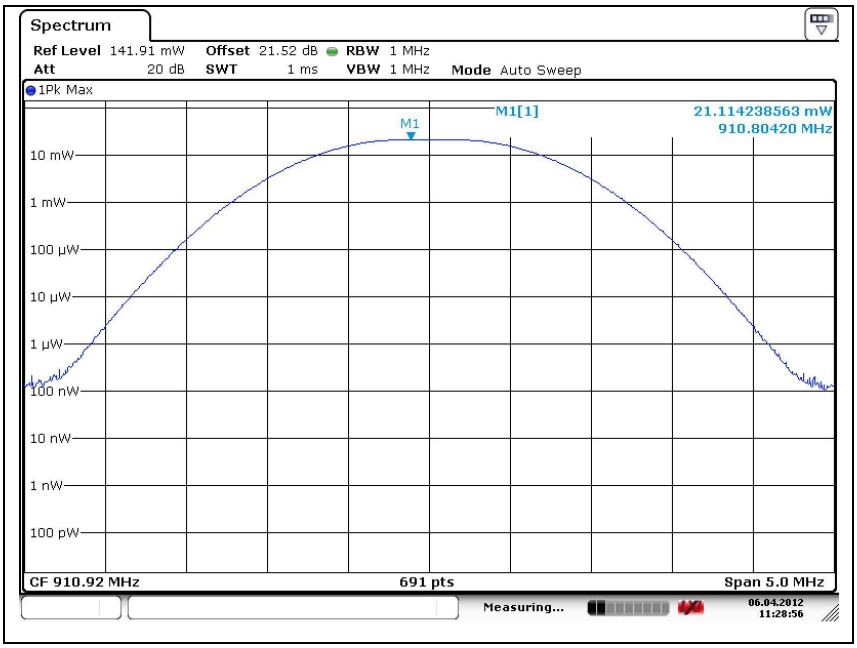
Limit

For frequency hopping systems operating in the 902 ~ 928 MHz band: 1 watt for systems employing at least 50 hopping channels; and, 0.25 watts for systems employing less than 50 hopping channels, but at least 25 hopping channels, as permitted under paragraph (a)(1)(i) of this section.

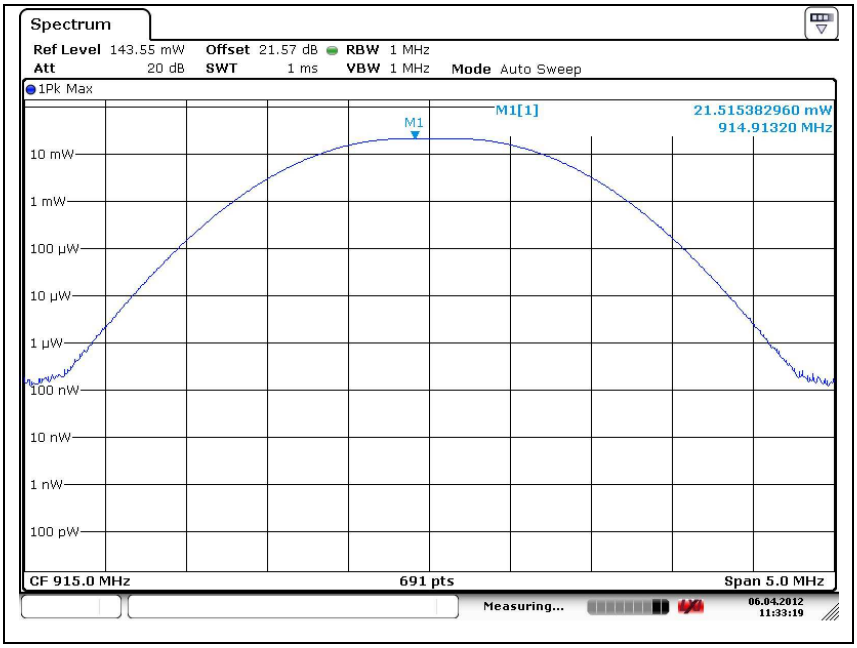
Test results

Frequency(㎒)	Output power (W)	Limit (W)
910.92	0.021	0.25
915.00	0.021	0.25
919.08	0.021	0.25

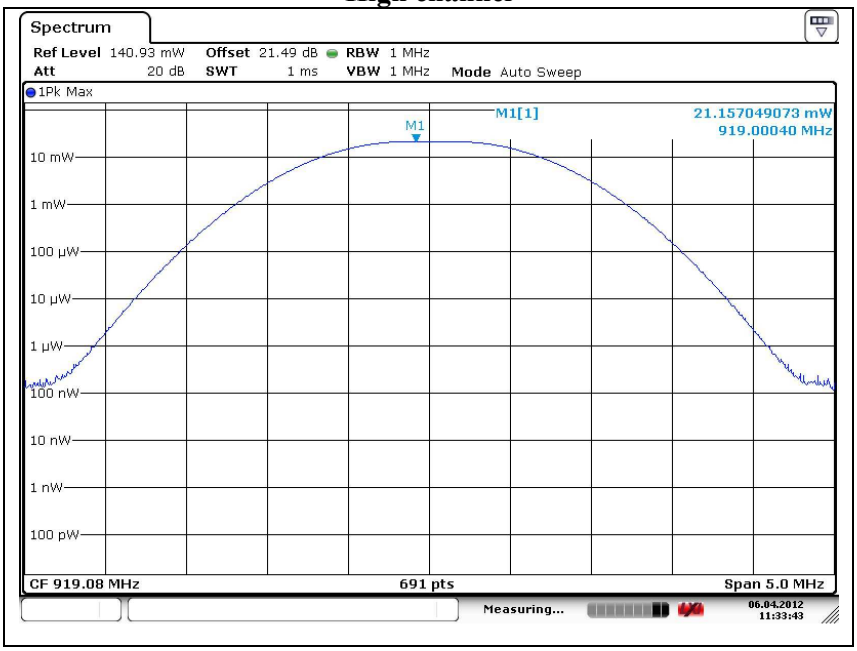
Low channel



Middle channel

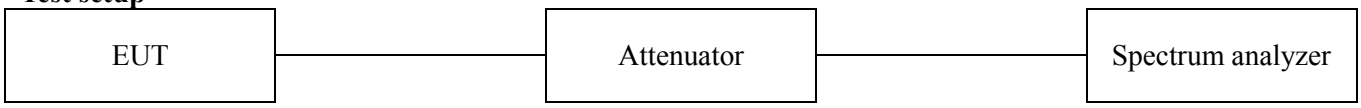


High channel



2.1.2 Conducted spurious emission & band edge

Test setup



Test procedure for band edge

1. Use the following spectrum analyzer setting
   Center frequency: Low, middle and high channel.
   Span = wide enough to capture the peak level of the emission operating on the channel closest to the band edge, as well as any modulation products which fall outside of the authorized band of operation.
   RBW = 100 ㎑
   VBW = 100 ㎑ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
2. Allow the trace to stabilize. Set the marker on the emission at the band edge, or on the highest modulation on product outside of the band, if this level is greater than that at the band edge. Enable the marker-delta function, then use the marker-to-peak function to move the marker to the peak of the in-band emission

Test procedure for spurious emission

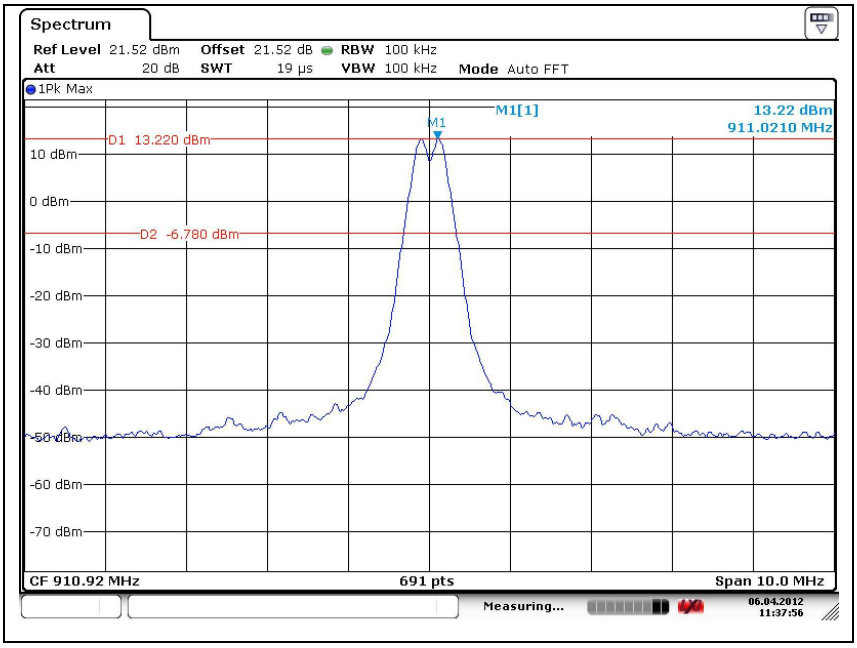
1. Use the following spectrum analyzer setting
   Center frequency: Low, middle and high channel.
   Span = wide enough to capture the peak level of the emission operating on the channel closest to the band edge, as well as any modulation products which fall outside of the authorized band of operation.
   RBW = 100 ㎑
   VBW = 100 ㎑ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
2. Allow the trace to stabilize. Set the marker on the peak of any spurious emission recorded.

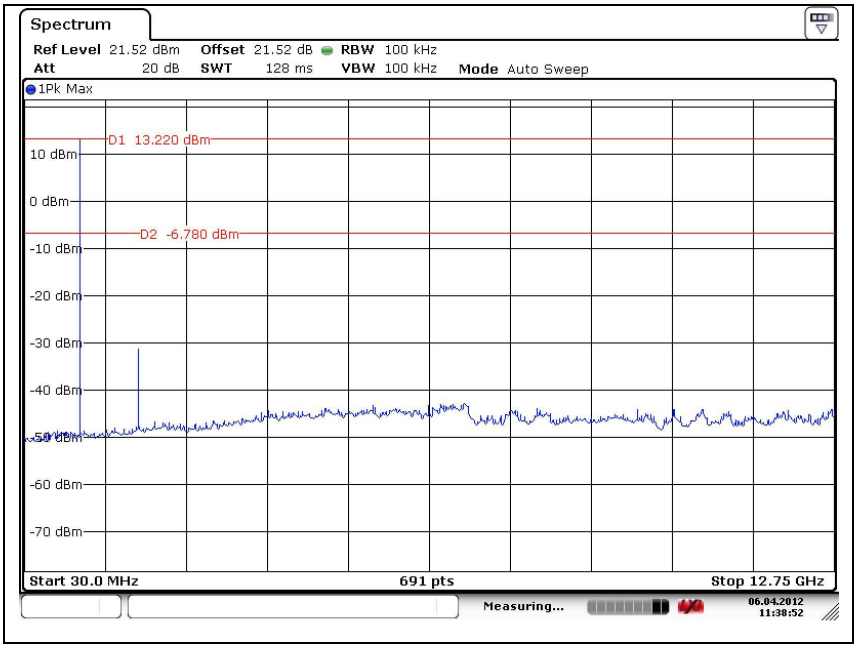
Limit

In any 100 ㎑ bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 ㏈ below that in the 100 ㎑ bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval , as permitted under paragraph(b)(3) of this section , the attenuation required under this paragraph shall be 30 ㏈ instead of 20 ㏈. Attenuation below the general limits specified in section 15.209(a) is not required. In addition, radiated emission which in the restricted band, as define in section 15.205(a), must also comply the radiated emission limits specified in section 15.209(a) (see section 15.205(c))

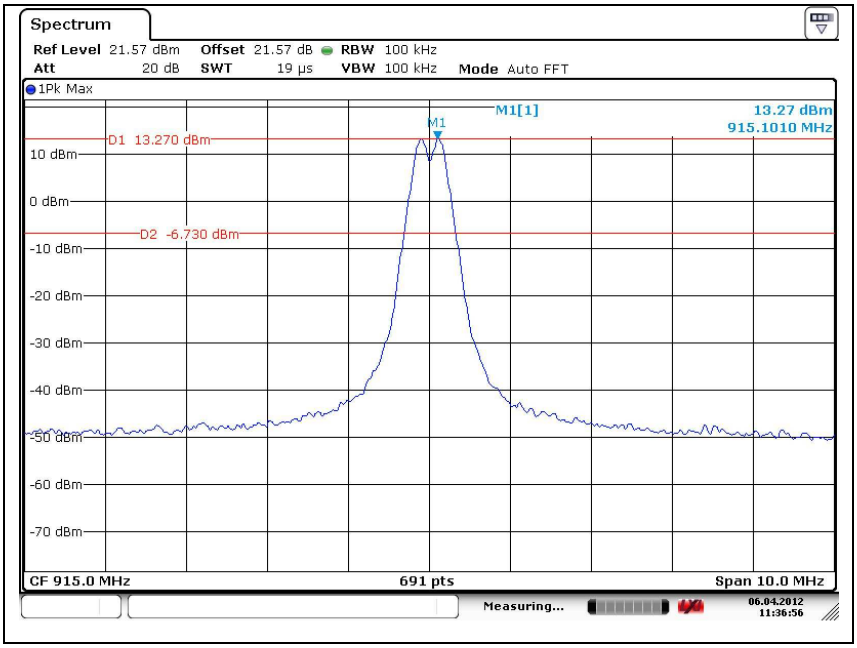
Test results

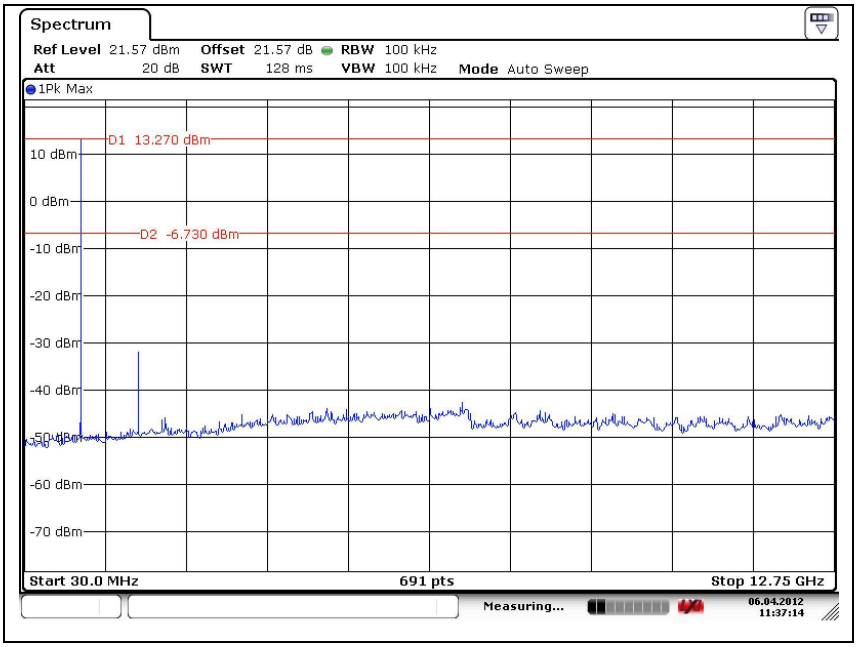
Low channel



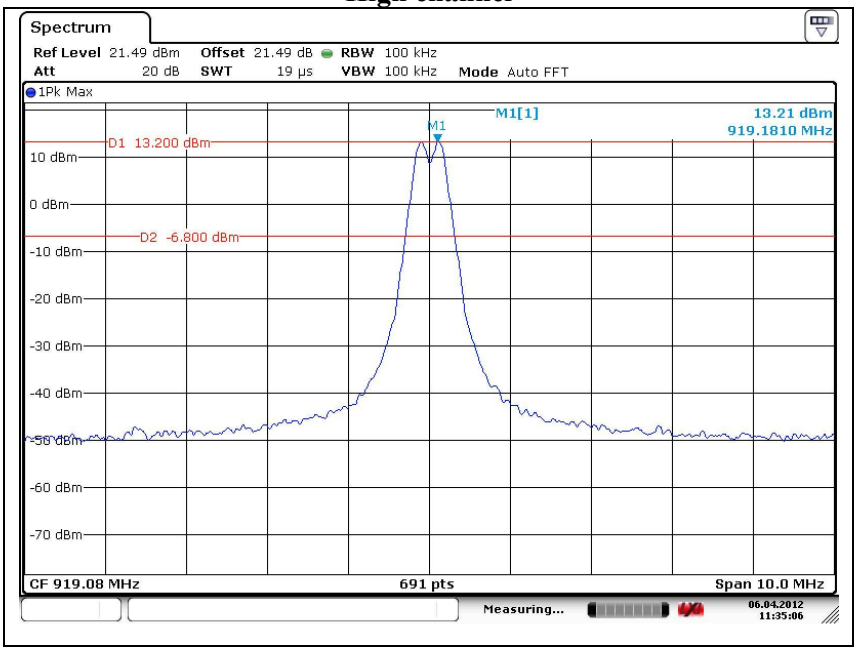


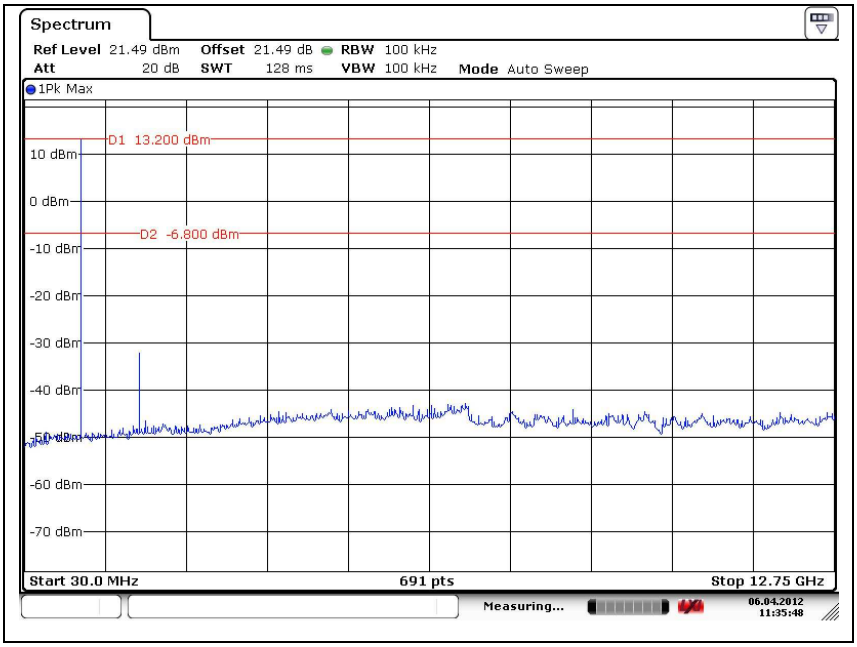
Middle channel



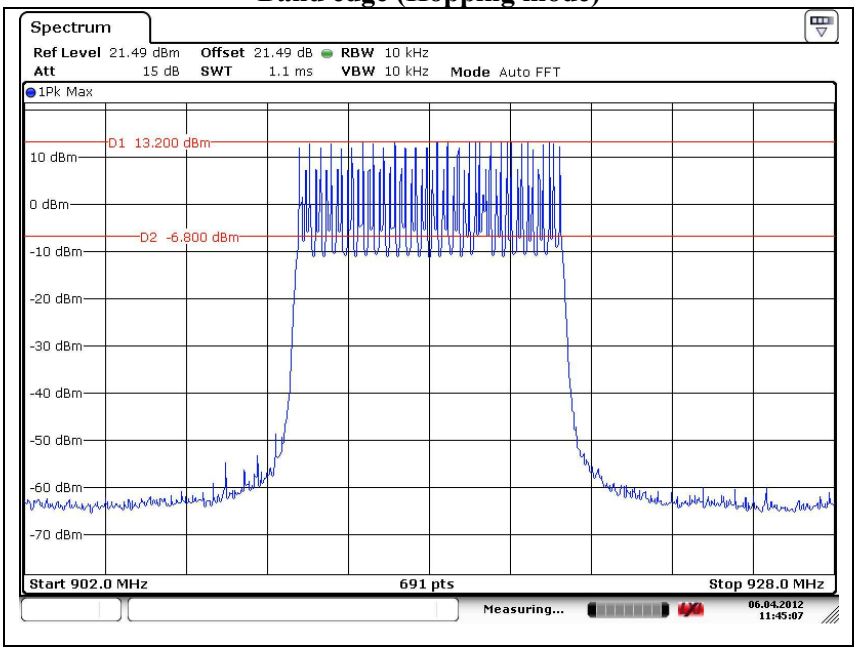


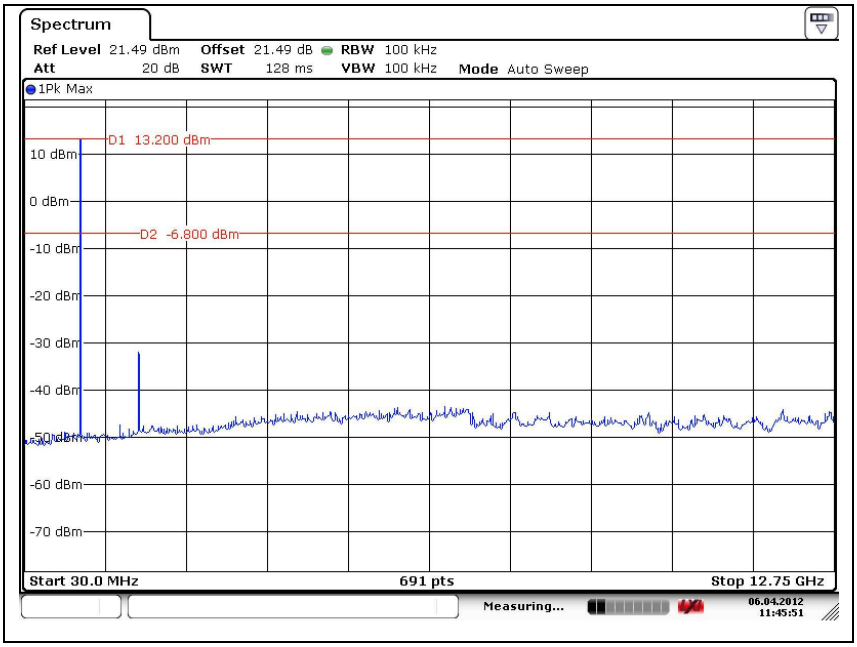
High channel





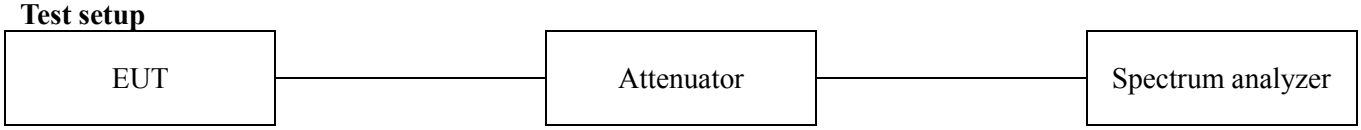
Band edge (Hopping mode)





2.1.3 20 dB bandwidth & 99 % occupied bandwidth

Test setup



Test procedure

1. Use the following spectrum analyzer setting
   Center frequency: Lowest, middle and highest channels
   Span = 1 ㎒ (Approximately 2 to 3 times the 20 dB bandwidth, centered on a hopping channel)
   RBW = 10 ㎑ (≥ 1% of the span)
   VBW = 10 ㎑ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
2. The EUT should be transmitting at its maximum data rate. Allow the trance to stabilize. Use the marker-to-peak function to set the marker to the peak of the emission. Use the marker-delta function to measure 20 dB down on side of the emission. Reset the marker-delta function, and move the marker to the other side of the emission, until it is (as close as possible to) even with the reference marker level.

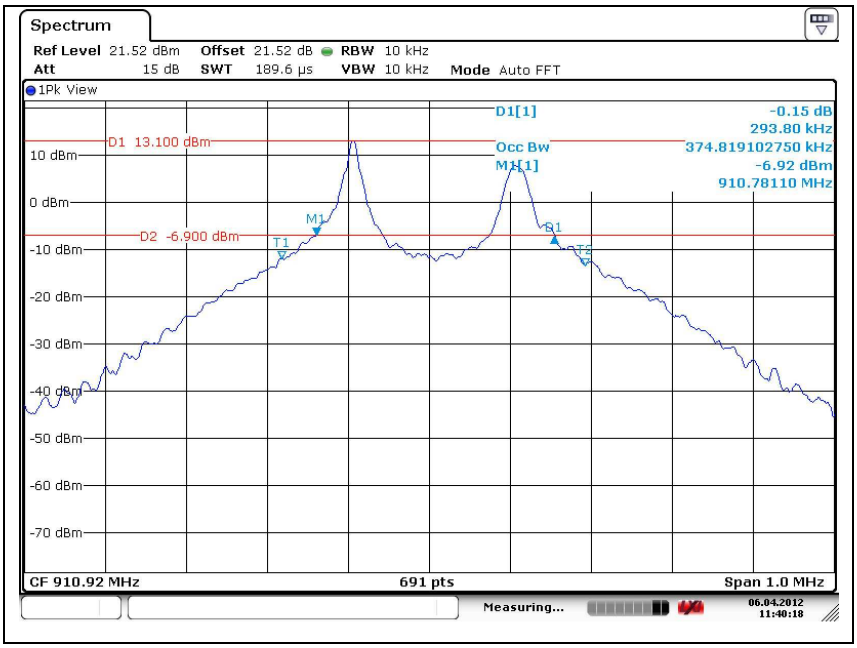
Limit

Not applicable

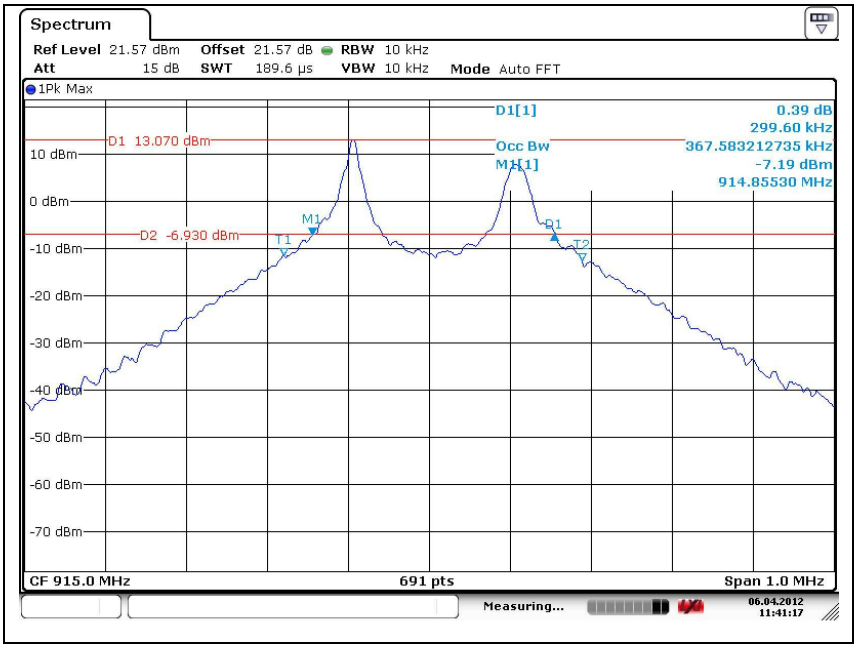
Test results

Frequency(㎒)	20 ㏈ bandwidth(㎑)	99 % occupied bandwidth(㎑)
910.92	293.80	374.82
915.00	299.60	367.58
919.08	296.70	344.43

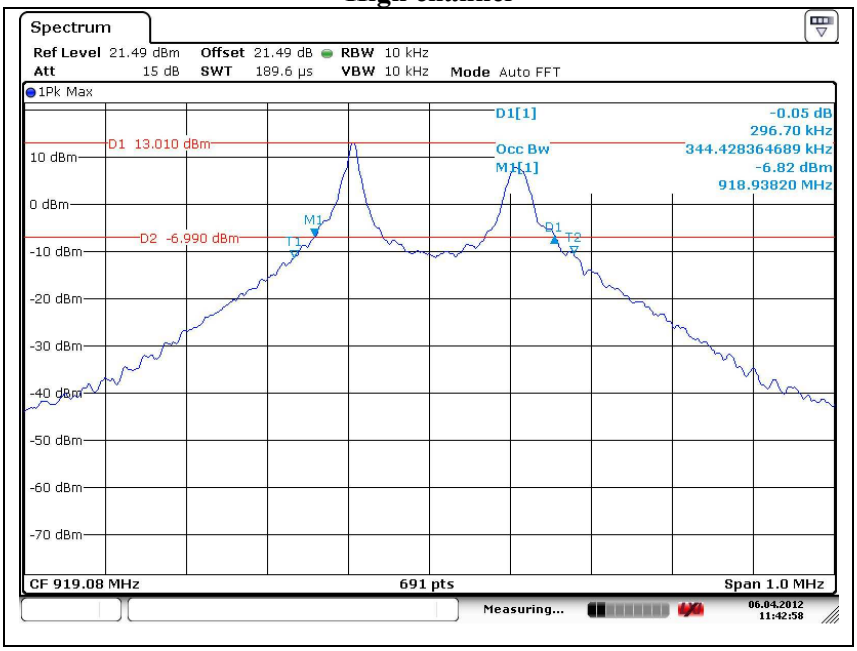
Low channel



Middle channel

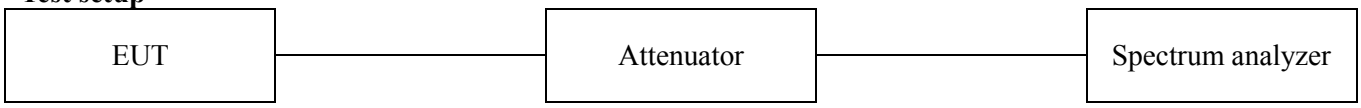


High channel



2.1.4 Frequency separation

Test setup



Test procedure

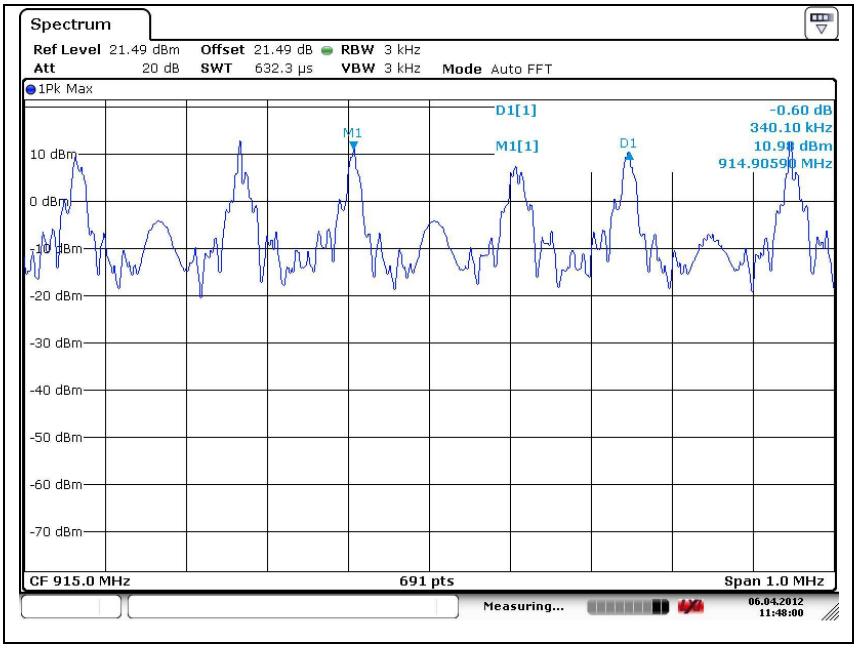
1. The EUT must have its hopping function enabled.
2. Use the following spectrum analyzer setting
   Span = 1 ㎒ (wide enough to capture the peaks of two adjacent channels)
   RBW = 3 ㎑ (≥ 1% of the span)
   VBW = 3 ㎑ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
3. All the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels.

Limit

Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 ㎑ or the 20 ㏈ bandwidth of the hopping channel, whichever is greater.

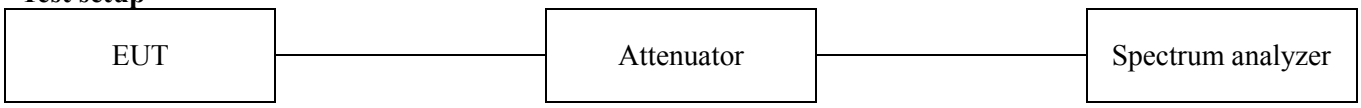
Test results

Operation mode	Channel separation(㎑)	Minimum bandwidth (㎑)
Hopping mode	340	25



2.1.5 Number of hopping frequency

Test setup



Test procedure

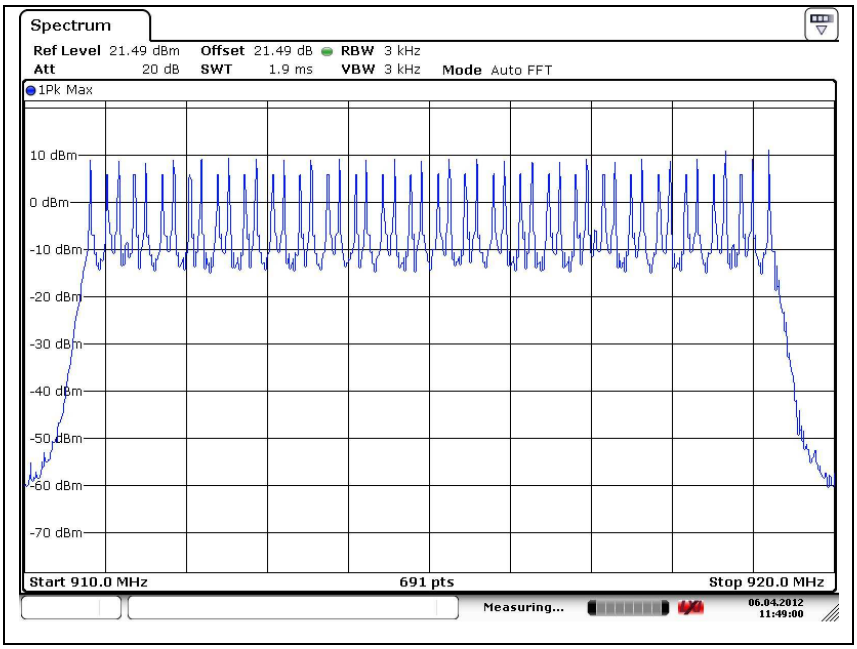
1. The EUT must have its hopping function enabled.
2. Use the following spectrum analyzer setting
   Frequency range: 910 ㎒ ~ 920 ㎒
   Span = the frequency band of operation
   RBW = 3 ㎑ (≥ 1% of the span)
   VBW = 3 ㎑ (≥ RBW)
   Sweep = auto
   Detector function = peak
   Trace = max hold
3. All the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels.

Limit

For frequency hopping systems operating in the 902 ~ 928 MHz band: 1 watt for systems employing at least 50 hopping channels; and, 0.25 watts for systems employing less than 50 hopping channels, but at least 25 hopping channels, as permitted under paragraph (a)(1)(i) of this section.

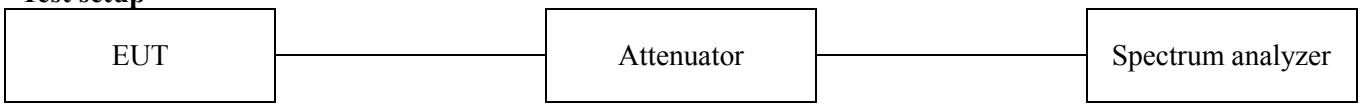
Test results

Operation mode	Number of hopping frequency	Limit
GFSK	25	≥ 25



2.1.6 Time of occupancy (Dwell time)

Test setup



Test procedure

1. Use the following spectrum analyzer setting
   Operation frequency: center frequency
   Span = Zero span, centered on a hopping channel
   RBW = 300 ㎑
   VBW = 300 ㎑ (≥ RBW)
   Sweep = as necessary to capture the entire dwell time per hopping channel
   Detector function = peak
   Trace = max hold

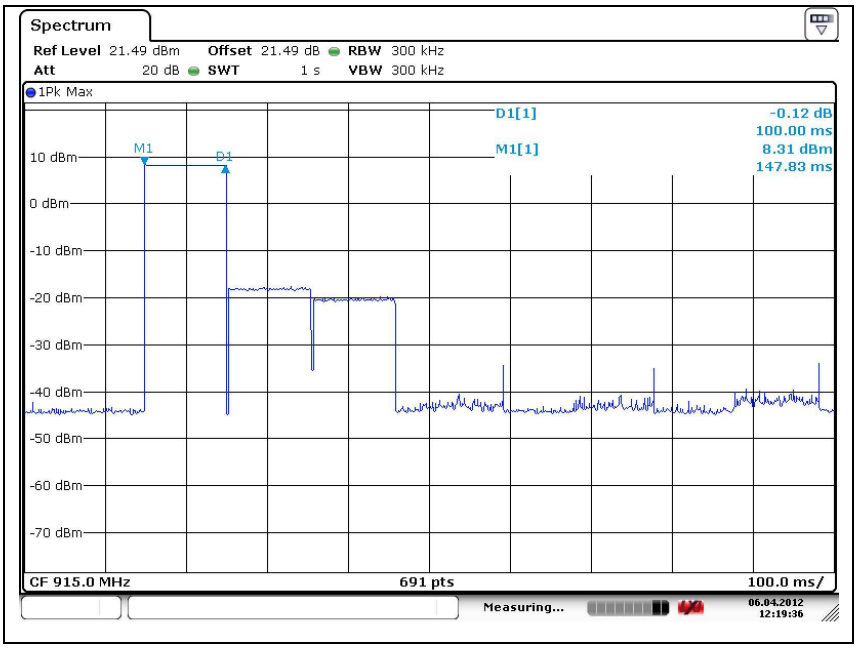
Limit

For frequency hopping systems operating in the 902 ~ 928 ㎒ band: if the 20 ㏈ bandwidth of the hopping channel is less than 250 ㎑, the system shall use at least 50 hopping frequencies and the average time of occupancy on any frequency shall not be greater than 0.4 seconds within a 20 second period; if the 20 ㏈ bandwidth of the hopping channel is 250 ㎑ or greater, the system shall use at least 25 hopping frequencies and the average time of occupancy on any frequency shall not be greater than 0.4 seconds within a 10 second period. The maximum allowed 20 ㏈ bandwidth of the hopping channel is 500 ㎑.

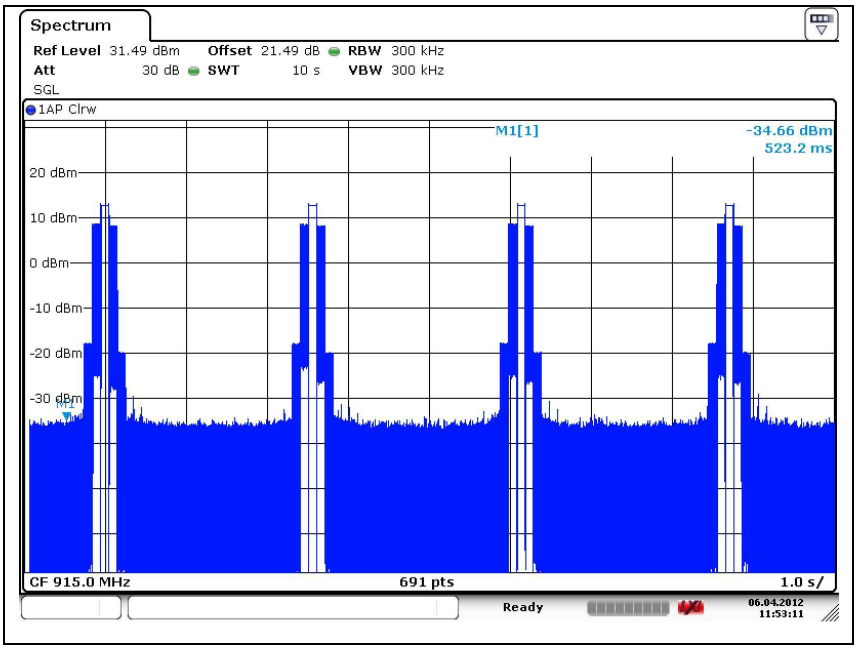
Test results

Frequency (㎒)	Dwell time (ms)	Transmission occurred	Result (㎳)	Limit (㎳)
915	100	4	400	400

Dwell time



Transmission occurred



2.1.7 Radiated spurious emission & band edge

Test location
Testing was performed at a test distance of 3 meter Open Area Test Site

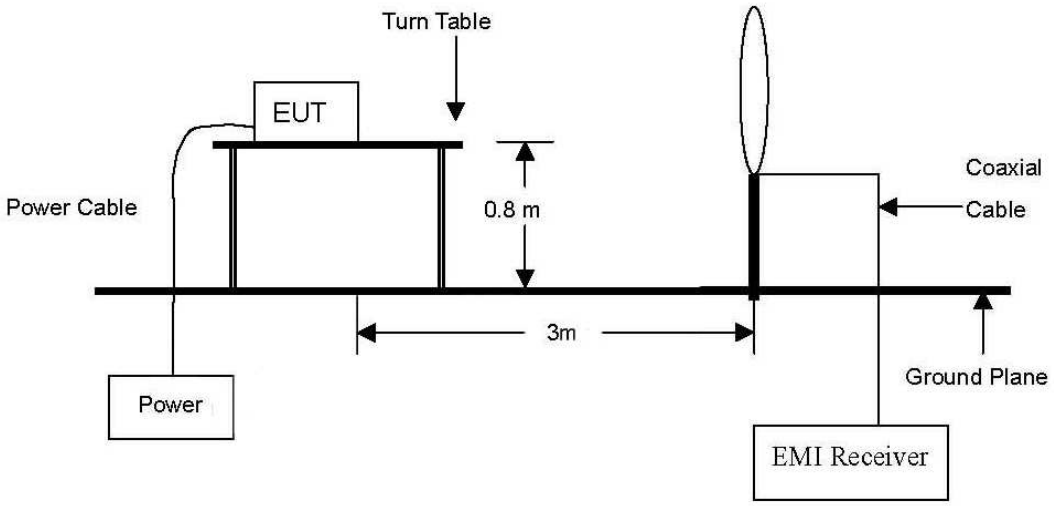
Test procedures
[9 ㎑ to 30 ㎒]
The EUT was placed on the top of a rotating table 0.8 meter above the ground at a 3 meter OATS. The table was rotated 360 degrees to determine the position of the highest radiation. Then antenna is a loop antenna is fixed at one meter above the ground to determine the maximum value of the field strength. Both parallel and perpendicular of the antenna are set to make the measurement. For each suspected emission, the EUT was arranged to its worst case and then the table was turned from 0 degrees to 360 degrees to find the maximum reading. The test-receiver system was set to Quasi-peak function and specified bandwidth with maximum hold mode.

The spectrum analyzer is set to:
1. The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer 200 ㎐ for Quasi-peak detection (QP) at frequency below 9 ㎑~ 150 ㎑.
2. The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer 9 ㎑ for Quasi-peak detection (QP) at frequency below 150 ㎑~ 30 ㎒.

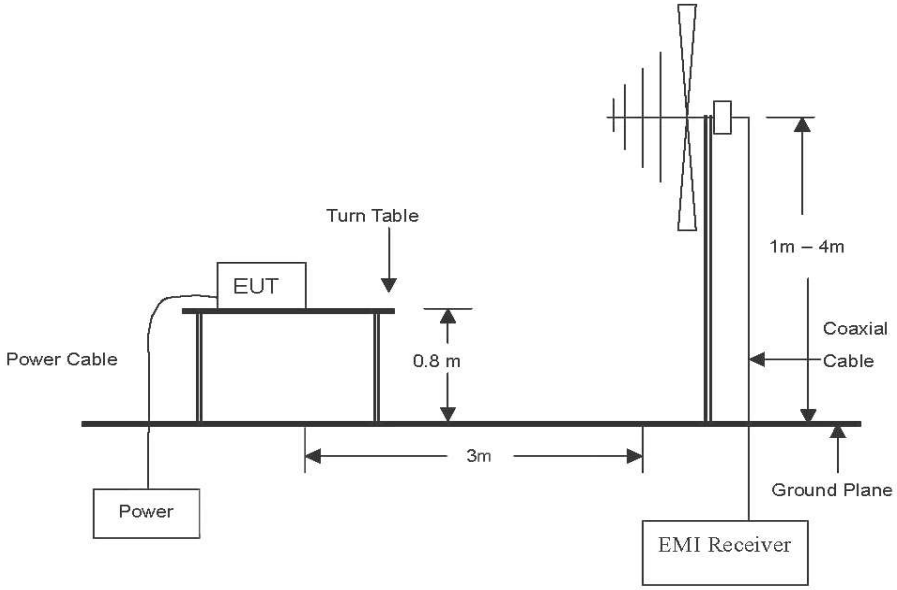
[30 ㎒ to 1 ㎓ and 1 ㎓ to 24 ㎓]
The height of the measuring antenna was varied between 1 to 4 m and the table was rotated a full revolution in order to obtain maximum values of the electric field intensity.
The measurement was made in both the vertical and horizontal polarization, and the maximum value is presented in the report.

The spectrum analyzer is set to:
1. The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer 120 ㎑ for Peak detection (PK) or Quasi-peak detection (QP) at frequency below 1 ㎓.
2. The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer is 1 ㎒ for Peak detection at frequency above 1 ㎓.
3. The resolution bandwidth of test receiver/spectrum analyzer is 1 ㎒ and the video bandwidth is 10 ㎐ for Average detection (AV) at frequency above 1 ㎓.

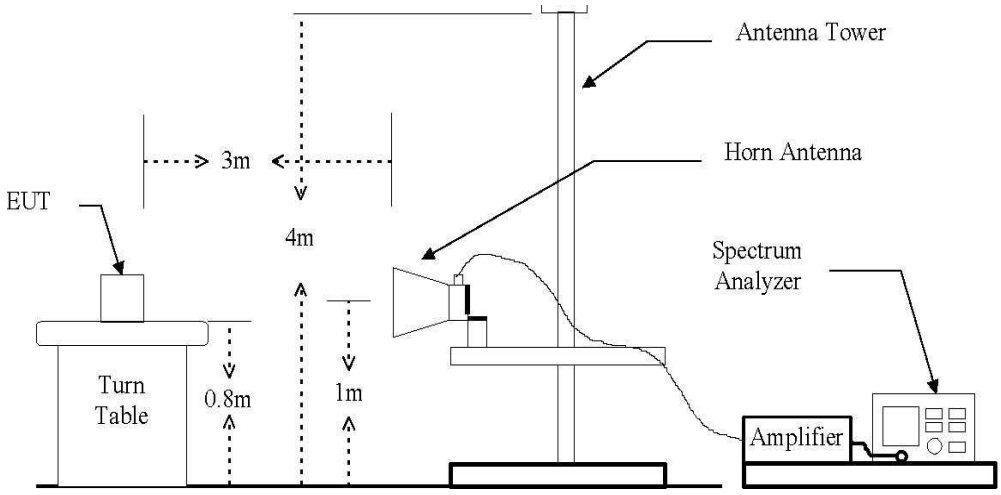
The diagram below shows the test setup that is utilized to make the measurements for emission from 9 ㎑ to 30 ㎒ Emissions.



The diagram below shows the test setup that is utilized to make the measurements for emission from 30 ㎒ to 1 ㎓ emissions.



The diagram below shows the test setup that is utilized to make the measurements for emission from 1 ㎓ to 24 ㎓ emissions.



Limit

According to 15.209(a), for an intentional radiator devices, the general required of field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values：

Frequency (㎒)	Distance (Meters)	Radiated (㎶/m)
0.009 ~ 0.490	300	2400 / F(㎑)
0.490 ~ 1.705	30	24000 / F(㎑)
1.705 ~ 30.0	30	30
30 ~ 88	3	100**
88 ~ 216	3	150**
216 ~ 960	3	200**
Above 960	3	500

**Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this Section shall not be located in the frequency bands 54 ~ 72 ㎒, 76 ~ 88 ㎒, 174 ~ 216 ㎒ or 470 ~ 806 ㎒. However, operation within these frequency bands is permitted under other sections of this Part, e.g., Sections 15.231 and 15.241.

Test results (Below 30 ㎒)

Radiated emissions		Ant.	Correction factors			Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Pol.	Ant. Factor (dB/m)	Cable loss (dB)	F_d (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
Not applicable								

※ Remark

1. All spurious emission at channels are almost the same below 30 ㎒, so that N/A was chosen at representative in final test.
2. Actual = Reading + Ant. factor + Cable loss + F_d
3. $F_d = 40\log(D_m / D_s)$
   Where:
   F_d = Distance factor in dB
   D_m = Measurement distance in meters
   D_s = Specification distance in meters

Test results (Below 1 000 ㎒)

The frequency spectrum from 30 ㎒ to 1 000 ㎒ was investigated.

Radiated emissions		Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
Emission levels are not reported much lower than the limits by over 20 dB							

※ Remark

1. All spurious emission at channels are almost the same below 1 ㎓, so that high channel was chosen at representative in final test.
2. Actual = Reading + Ant. factor + Amp + CL (Cable loss)
3. Detector mode: Quasi peak
4. To get a maximum emission level from the EUT, the EUT was moved throughout the XY, XZ and YZ planes.

Test results (Above 1 000 ㎒) – Basic model

Low channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2732.76	55.47	Peak	V	29.01	-38.33	46.15	74.00	27.85

Middle channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2745.00	54.88	Peak	V	29.03	-38.31	45.60	74.00	28.40

High channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2757.24	55.73	Peak	V	29.06	-38.29	46.50	74.00	27.50

※ Remark

1. "*" means the restricted band.
2. Measuring frequencies from 1 ㎓ to the 10th harmonic of highest fundamental frequency.
3. Radiated emissions measured in frequency above 1 000 ㎒ were made with an instrument using peak/average detector mode.
4. Average test would be performed if the peak result were greater than the average limit.
5. Actual = Reading + Ant. factor + Amp + CL (Cable loss)
6. To get a maximum emission level from the EUT, the EUT was moved throughout the XY, XZ and YZ planes.

Test results (Above 1 000 ㎒) – Variant model

Low channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2732.76	55.80	Peak	V	29.01	-38.33	46.48	74.00	27.52

Middle channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2745.00	55.23	Peak	V	29.03	-38.31	45.95	74.00	28.05

High channel

Radiated emissions			Ant.	Correction factors		Total	Limit	
Frequency (㎒)	Reading (dB㎶)	Detector mode	Pol.	Ant. factor (dB/m)	Amp + CL (dB)	Actual (dB㎶/m)	Limit (dB㎶/m)	Margin (dB)
2757.24	55.91	Peak	V	29.06	-38.29	46.68	74.00	27.32

※ Remark

1. "*" means the restricted band.
2. Measuring frequencies from 1 ㎓ to the 10th harmonic of highest fundamental frequency.
3. Radiated emissions measured in frequency above 1 000 ㎒ were made with an instrument using peak/average detector mode.
4. Average test would be performed if the peak result were greater than the average limit.
5. Actual = Reading + Ant. factor + Amp + CL (Cable loss)
6. To get a maximum emission level from the EUT, the EUT was moved throughout the XY, XZ and YZ planes.

Appendix A. Test equipment used for test

Equipment	Manufacturer	Model	Calibration due.
Spectrum Analyzer	R&S	FSV30	2013.01.10
Vector Signal Generator	R&S	SMBV2100A	2013.01.10
DC Power Supply	Agilent	6632B	2012.05.06
DC Power Supply	SMTECHNO	SDP 30-5D	2012.11.14
Trilog-Broadband Antenna	SCHWARZBECK	VULB 9168	2013.10.25
Horn Antenna	A.H. System	SAS-571	2013.03.22
High Pass Filter	Wainwright Instrument	WHKX1.5/15G-6SS	2013.03.30
Preamplifier	A.H. System	PAM-0118	2012.05.04
EMI Test Receiver	R&S	ESVS10	2012.05.20

Peripheral devices

Device	Manufacturer	Model No.	Serial No.
N/A			

Appendix B. Test setup photos

Radiated field emissions